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Special Issue Reprint

Advancements in Optical Measurement Devices and Technologies

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The Special Issue “Advancements in Optical Measurement Devices and Technologies” brings together state-of-the-art research on optical metrology techniques and devices that enhance precision measurement across scientific and industrial applications. This collection highlights innovative sensors, imaging and spectroscopy methods, advanced interferometry, and practical measurement systems for microfluidics, quantum standards, surface characterization, and laser scanning, demonstrating their contributions to metrological accuracy and real-world deployment.

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